

**Features**

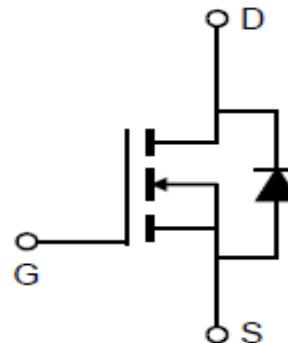
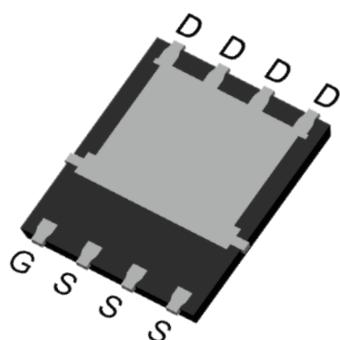
- AEC-Q101 qualified
- Low on resistance
- Low reverse transfer capacitances
- 100% single pulse avalanche energy test
- 100%  $\Delta V_{DS}$  test
- Pb-Free plating / Halogen-Free / RoHS compliant

**Key Parameters**

$V_{DS}$	40V
$R_{DS(on)}(typ.)$	2.4mΩ
$I_D$ (Silicon limit)	122A
$I_D$ (Package limit)	80A
$V_{th}$	3V
$C_{iss}@10V$	4655pF
$Q_{gd}$	14.4nC

**Applications**

- Motor Control and Drive
- Charge/Discharge for Battery Management System
- Synchronous Rectifier for SMPS

**DFN5\*6****Marking & Packing Information**

Part #	Package	Marking	Tube/Reel	Qty(pcs)
SQJ422EP-T1_GE3-CN	DFN5*6	027N04NA	Reel	3000/box

**Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Drain-source voltage	V <sub>DS</sub>	40	V
Gate-Source voltage	V <sub>GS</sub>	±20	V
Continuous drain current T <sub>C</sub> = 25°C (Silicon limit) T <sub>C</sub> = 25°C(Package limit) T <sub>C</sub> = 100°C (Package limit)	I <sub>D</sub>	122	A
		80	
		80	
Pulsed drain current (T <sub>C</sub> = 25°C, t <sub>p</sub> limited by T <sub>jmax</sub> )	I <sub>D</sub> pulse	487	A
Avalanche energy, single pulse (L=0.5mH, R <sub>g</sub> =25Ω)	E <sub>AS</sub>	529	mJ
Power dissipation (T <sub>C</sub> = 25°C)	P <sub>tot</sub>	71	W
Operating junction and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55...+175	°C

**Thermal Resistance**

Parameter	Symbol	Max	Unit
Thermal resistance, junction – case.	R <sub>thJC</sub>	2.10	°C/W
Thermal resistance, junction – ambient(min. footprint)	R <sub>thJA</sub>	75	

**Electrical Characteristic (at T<sub>j</sub> = 25 °C, unless otherwise specified)**
**Static Characteristic**

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Drain-source breakdown voltage	BV <sub>DSS</sub>	40	-	-	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA
Gate threshold voltage	V <sub>GS(th)</sub>	2.0	3.0	4.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA
Zero gate voltage drain current	I <sub>DSS</sub>	-	-	1	μA	V <sub>DS</sub> =40V, V <sub>GS</sub> =0V
		-	-	100		T <sub>j</sub> =25°C T <sub>j</sub> =125°C
Gate-source leakage current	I <sub>GSS</sub>	-	-	100	nA	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	2.4	2.75	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =60A, T <sub>j</sub> =25°C

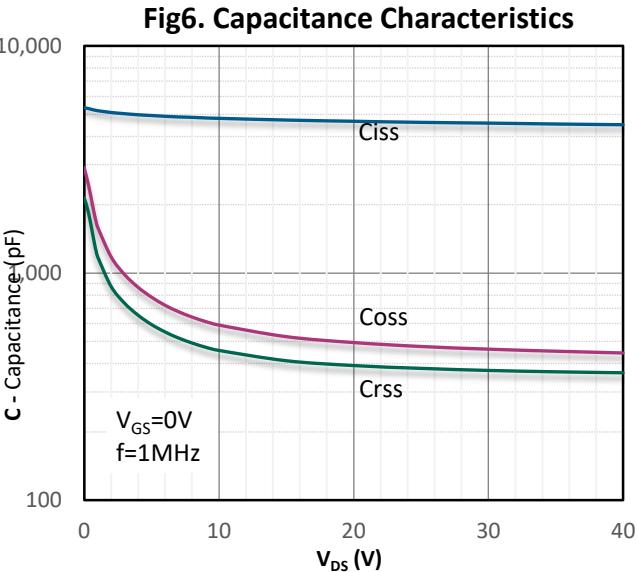
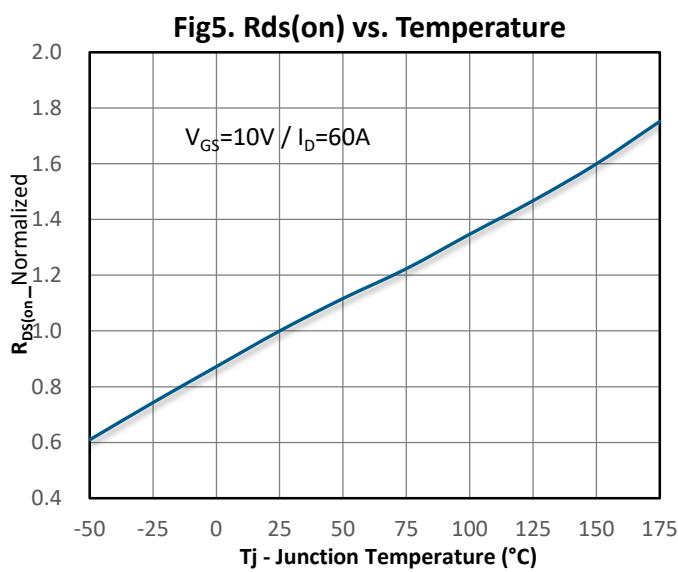
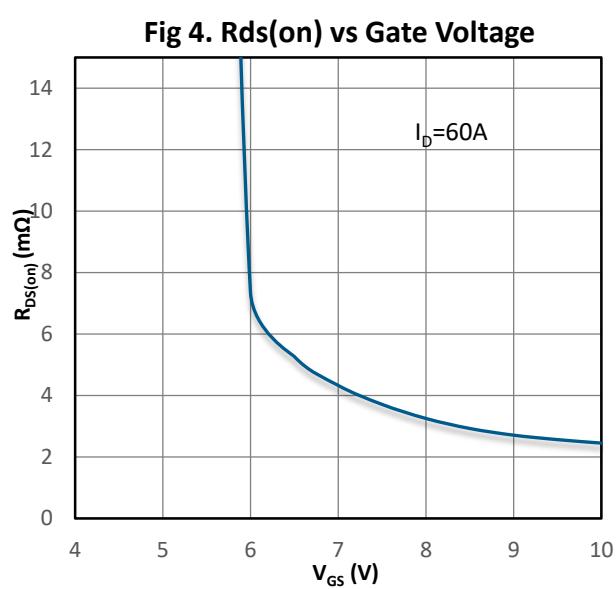
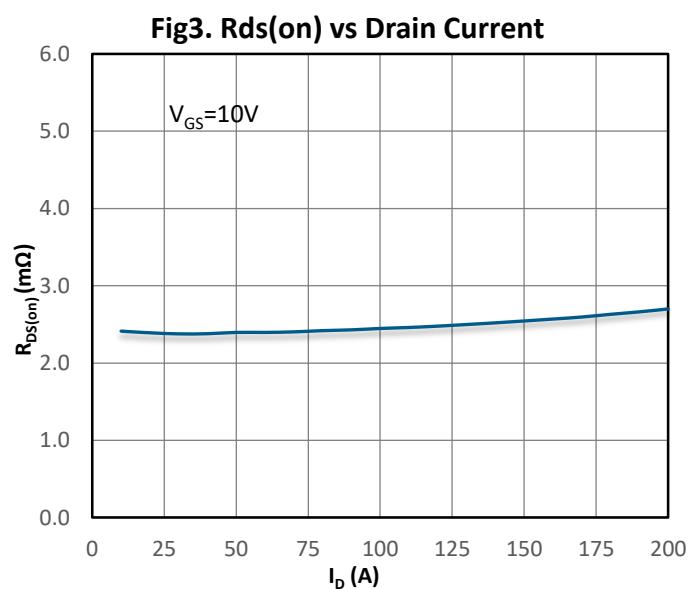
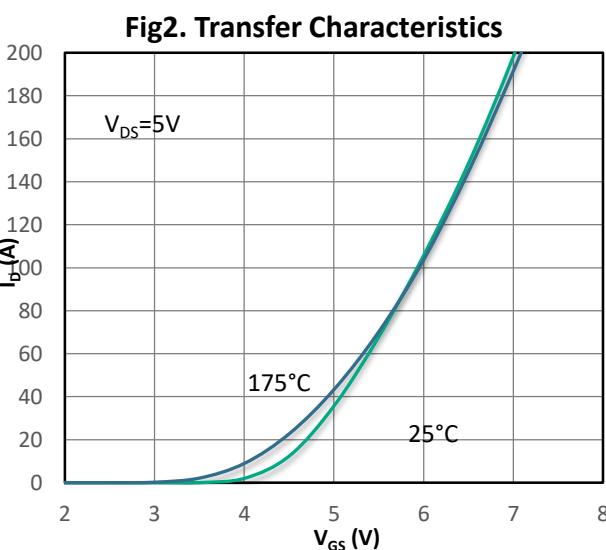
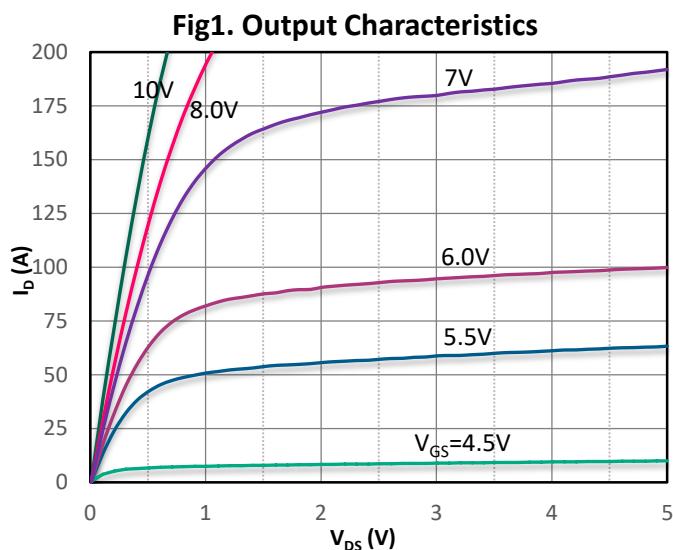
**Dynamic Characteristic**

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Input Capacitance	C <sub>iss</sub>	-	4655	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =20V, f=1MHz
Output Capacitance	C <sub>oss</sub>	-	494	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	391	-		
Gate Total Charge	Q <sub>G</sub>	-	73	-	nC	V <sub>GS</sub> =10V, V <sub>DS</sub> =20V, I <sub>D</sub> =50A, f=1MHz
Gate-Source charge	Q <sub>gs</sub>	-	30	-		
Gate-Drain charge	Q <sub>gd</sub>	-	14.4	-		
Turn-on delay time	t <sub>d(on)</sub>	-	14	-	ns	V <sub>GS</sub> =10V, V <sub>DD</sub> =20V, R <sub>G_ext</sub> =3Ω
Rise time	t <sub>r</sub>	-	48	-		
Turn-off delay time	t <sub>d(off)</sub>	-	34	-		
Fall time	t <sub>f</sub>	-	18	-		
Gate resistance	R <sub>G</sub>	-	2.8	-	Ω	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz

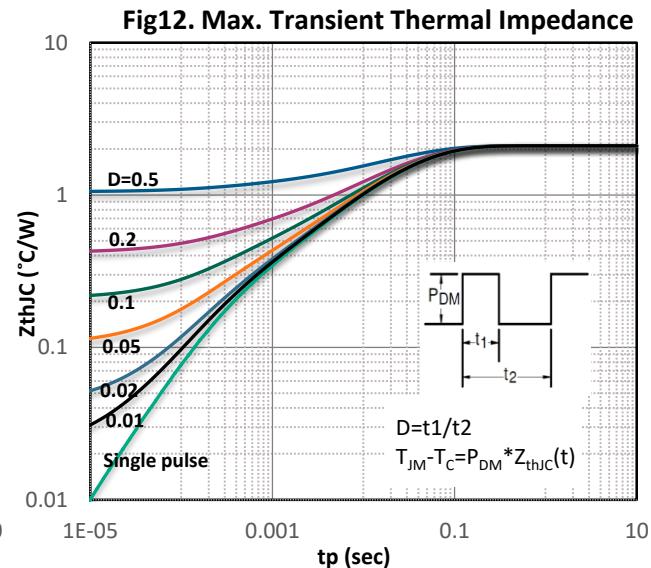
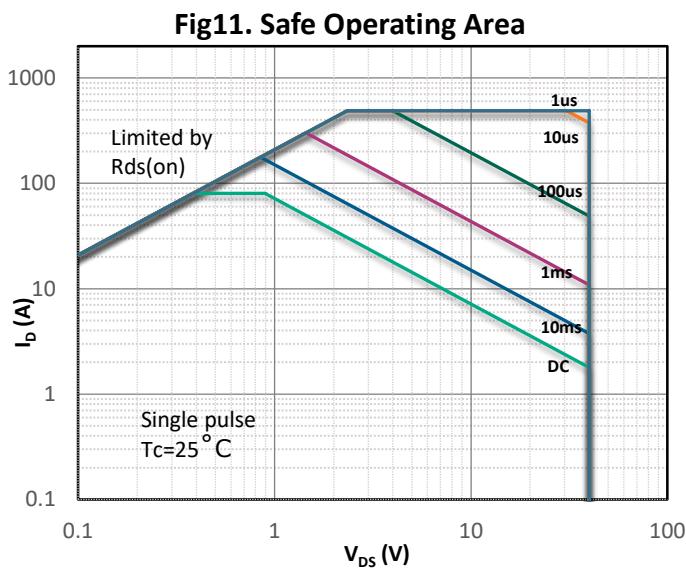
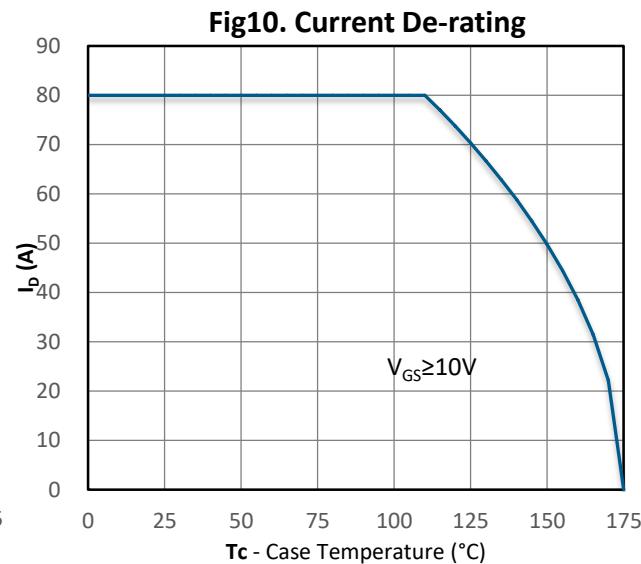
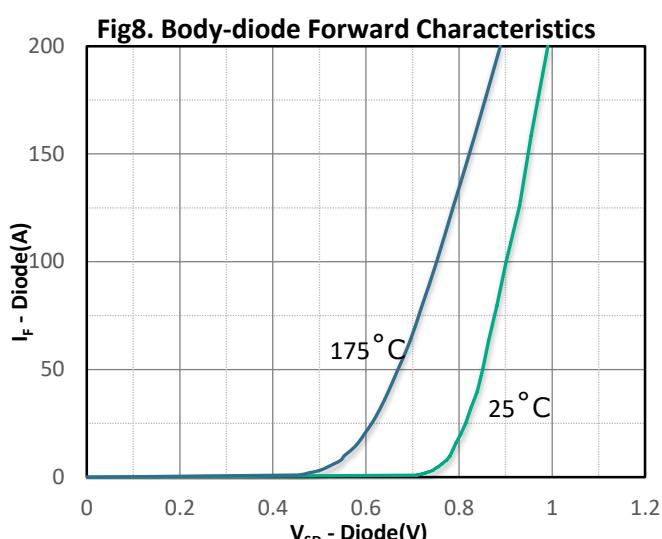
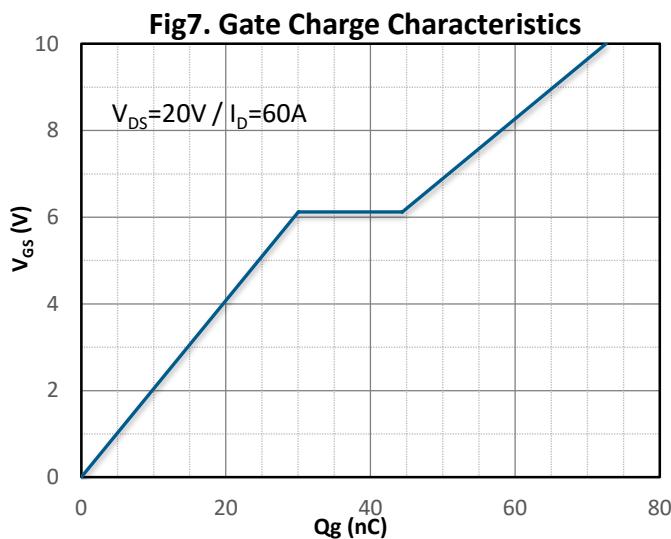
**Body Diode Characteristic**

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Diode Max Current	I <sub>s</sub>		-	80	A	-
Diode Forward Voltage	V <sub>SD</sub>	-	-	1.2	V	V <sub>GS</sub> =0V, I <sub>SD</sub> =60A
Diode Reverse Recovery Time	t <sub>rr</sub>	-	21	-	ns	I <sub>F</sub> =50A, dI/dt=100A/μs
Diode Reverse Recovery Charge	Q <sub>rr</sub>	-	8	-		

### Typical Characteristics Diagram

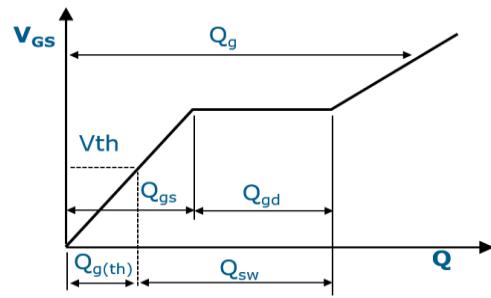
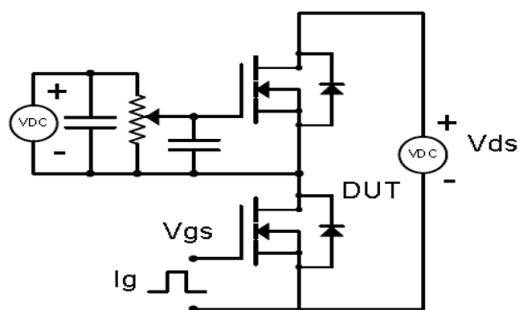


### Typical Characteristics Diagram

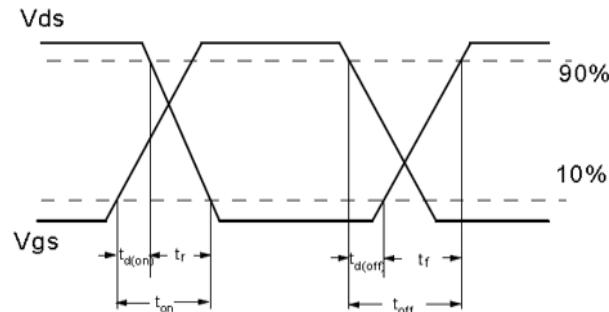
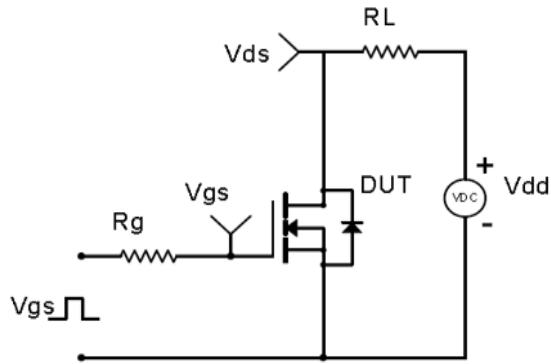


## Test Circuit & Waveform

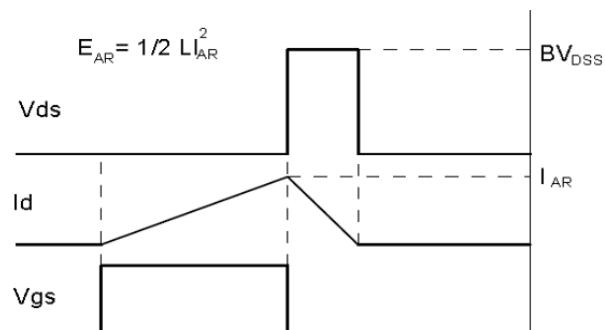
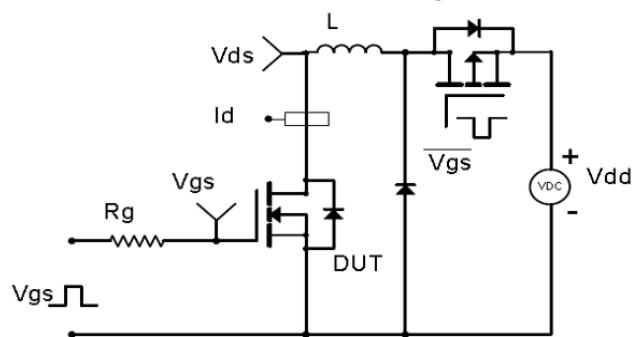
### Gate Charge Test Circuit & Waveform



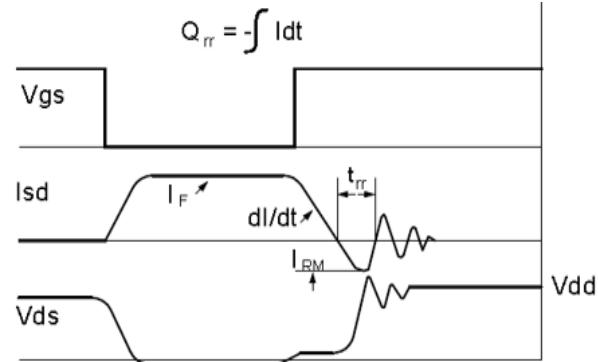
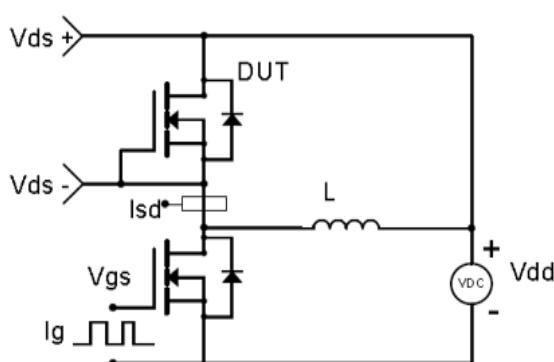
### MOSFET Switching Test Circuit & Waveform



### E<sub>AS</sub> Test Circuit & Waveform

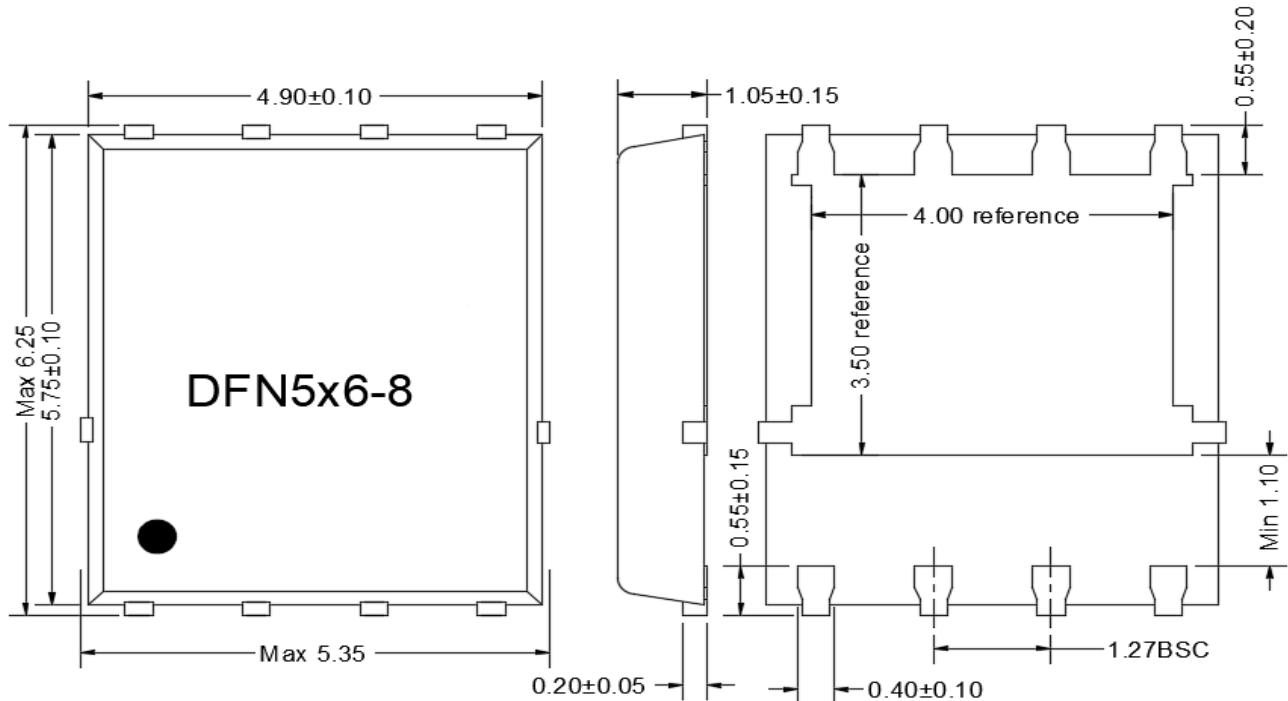


### Diode Recovery Test Circuit & Waveform



**Package Outline : DFN5\*6**

\*Dimensions in mm



**NOTICE**

The information presented in this document is for reference only. Involving product optimization and productivity improvement, ChipNobo reserves the right to adjust product indicators and upgrade some technical parameters. ChipNobo is entitled to be exempted from liability for any delay or non-delivery of the information disclosure process that occurs.

本文件中提供的信息仅供参考。涉及产品优化和生产效率改善，ChipNobo 有权调整产品指标和部分技术参数的升级，所出现信息披露过程存在延后或者不能送达的情形，ChipNobo 有获免责权。

The product listed herein is designed to be used with residential and commercial equipment, and do not support sensitive items and specialized equipment in areas where sanctions do exist. ChipNobo Co., Ltd or anyone on its behalf, assumes no responsibility or liability for any damages resulting from improper use.

此处列出的产品旨在民用和商业设备上使用，不支持确有制裁地区的敏感项目和特殊设备，ChipNobo 有限公司或其代表，对因不当使用而造成的任何损害不承担任何责任。

For additional information, please visit our website <http://www.chipnobo.com>, or consult your nearest Chipnobo sales office for further assistance.

欲了解更多信息，请访问我们的网站 <http://www.chipnobo.com>，或咨询离您最近的 Chipnobo 销售办事处以获得进一步帮助。